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### PATENT ABSTRACTS OF JAPAN

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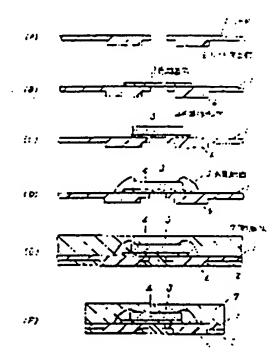
KIKUCHI TATSUO TAKASE YOSHIHISA

#### (54) SEMICONDUCTOR DEVICE AND MANUFACTURE THEREOF

PURPOSE: To obtain a highly accurate and highly reliable semiconductor device by placing a semiconductor chip through an insulating substrate on one group of highly accurate metal leads, connecting the leads to fine

metal wirings, and transfer molding them.

CONSTITUTION: A thin resin plate 3 is attached to leads I having protrusions 6, and electrodes on a semiconductor chip 4 are connected to the leads 1 by fine metal wirings 5. Then, the leads except the protrusions 6 are sealed with resins 2, 7, shape and size are determined and cut. According to this structure, a small-sized and thin semiconductor device having high dimensional accuracy and reliability is obtained without complicated structure like a both-side substrate only by employing metal leads of special shape at part, and is freferably adapted for an IC.



#### LEGAL STATUS

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[Date of sending the examiner's decision of rejection]

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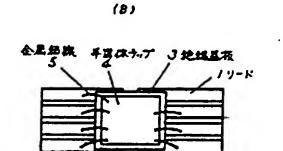
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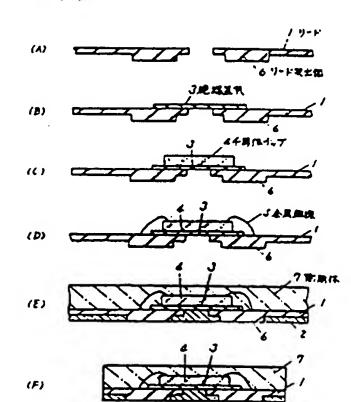
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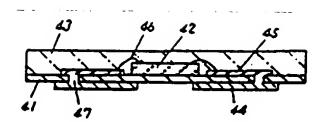
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